

Proposal List of Contract Beamline Experiments in 2000A

Proosal No.	Project Leader	Title of Experiment	Beamline No.
C00A16XU-300N	HIRAI, Yasuharu	Micro-analyses of Si surfaces and organic materials	BL16XU
C00A16XU-301N	HIROSE, Takayuki	X-ray Diffraction of Co-based magnetic thin film.	BL16XU
C00A16XU-302N	HIROSE, Jun	Crystallographic analysis of micro crystal Si films	BL16XU
C00A16XU-303N	SENO, Yoshiki	X-ray diffraction studies of LiNi O ₂ and Nd ₂ Fe ₁₄ B	BL16XU
C00A16XU-304N	HIRAI, You	Interface structure analysis of Copper interconnection thin films by X-ray deffraction	BL16XU
C00A16XU-305N	HIRAI, Yasuharu	Structure analysis of polyethylene films	BL16XU
C00A16XU-307N	KIMURA, Shigeru	X-ray diffraction measurements for thin films of Pb(ZrTi)O ₃ and other materials	BL16XU
C00A16XU-308N	YAMAGUCHI, Koji	Structural analysis of SiN thin film using X-ray deffraction measurements	BL16XU
C00A16XU-309N	AWAJI, Naoki	Study of TaO and PbZrTiO oxide films and magnetic thin films by x-ray fluorecence analysisi and x-ray diffraction	BL16XU
C00A16XU-310N	OZAKI, Shinji	XRF Analysis of Silicon , Tantalum Oxide Films	BL16XU
C00A16XU-311N	NISHINO, Junichi	Elemental analysis of Si wafer surface	BL16XU
C00A16XU-312N	NISHINO, Junichi	Elemental analysis of GaO thin film surface	BL16XU
C00A16XU-314N	IZUMI, Kouichi	Surface of Fe-oxide thin films by means of X-ray fluorecence analysis	BL16XU
C00A16XU-315N	TAKEMURA, Momoko	Trace element analysis on Si wafer using synchrotron radiation	BL16XU
C00A16XU-317N	HAGA, Koukichi	Characterization of LIGA-based Microstructures Using an X-ray Microprobe	BL16XU
C00A16XU-318N	LIU, Kuang-Yu	Microbeam Application Research for X-ray Fluorescence Analysis of Gallium Nitride	BL16XU
C00A16XU-320N	YAMAGUCHI, Koji	Characterization of Ferrite and Cementite in Steel Wires	BL16XU
C00A16XU-321N	TAKAHASHI, Mamoru	A Study of Thin-Dielectrics Structure by X-ray Scattering	BL16XU
C00A16XU-322N	NISHINO, Junichi	Crystallographic analysis of Si, Ta, and Ge film	BL16XU
C00A16XU-323N	NISHINO, Junichi	Crystallographic analysis of Ti film	BL16XU
C00A16XU-324N	LIU, Kuang-Yu	Crytal Structure Analysis of Lithium Oxide	BL16XU
C00A16XU-325N	OZAKI, Shinji	XD Analysisi of Ti, Co Films	BL16XU
C00A16XU-326N	SENO, Yoshiki	Structural Analysis of GeSbTe films	BL16XU
C00A16B2-400N	OKAMOTO, Tokuhiko	Local Structure Analysis on Si ₃ N ₄ , Pd/Fe-Co Perovuskite and Fe/SiO ₂ Metarials by Fluorescece	BL16B2
C00A16B2-401N	HIROSE, Jun	Study of Local Structure of electrode materials for chemical batteries.	BL16B2
C00A16B2-402N	IZUMI, Kouichi	Characterization of BaSrTiO ₃ /Si and other materials by total reflection XAFS	BL16B2
C00A16B2-403N	UEHARA, Yasushi	XAFS study of barium strontium titanate thin films	BL16B2
C00A16B2-404N	WATANABE, Takashi	Absolute measurement of the energy of x-ray absorption edges (K edges of Cu)	BL16B2
C00A16B2-405N	KUDO, Yoshihiro	The Structure Analysis of GaN by XAFS Method	BL16B2
C00A16B2-406N	TAKEISHI, Shunsaku	XAFS measurement of TaO and PbZrTiO oxide films	BL16B2

C00A16B2-407N	HAGA, Koukichi	Local atomic environment of vanadium ions in acid aqueous electrolytes	BL16B2
C00A16B2-408N	OKAMOTO, Tokuhiko	XAFS Study on LiNi O ₂ Secondary Battery	BL16B2
C00A16B2-409N	DEGUCHI, Hiroshi	Local Structure Analysis of Perovskite and Fluorite Solid State Electrolytes	BL16B2
C00A16B2-410N	KUDO, Yoshihiro	The Structure Analysis of Lithium Oxide by XAFS Method	BL16B2
C00A16B2-411N	OKAMOTO, Tokuhiko	XAFS Study on Local Structure of Ce and Zr in Industrial Catalyst. (Part 2)	BL16B2
C00A16B2-412N	WATANABE, Takashi	Local Structure Analysis of Copper interconnection thin films by XAFS	BL16B2
C00A16B2-413N	TERANISHI, Hideaki	Transmission XAFS of Pt alloy catalysts	BL16B2
C00A16B2-414N	OZAKI, Shinji	XAFS Analysis of Co , Ni Compounds for Secondary Battery	BL16B2
C00A16B2-415N	HIROSE, Jun	Local structure analysis of Ni and Co system electrode materials	BL16B2
C00A16B2-416N	YAMAMOTO, Tohru	XAFS Study on LaMnO ₃ -related Materials for Solid Oxide Fuel Cell(1)	BL16B2
C00A16B2-417N	OHSAWA, Michio	X-ray Reflectivity of Amorphous Carbon Films on Metal and Glass Substrates	BL16B2
C00A16B2-418N	TAKEMURA, Momoko	Structure Analyses of Spin Valve Multi-Layer Thin Films by X-Ray Reflection Measurement	BL16B2
C00A16B2-419N	UEHARA, Yasushi	X-ray reflective study of thin films of silicon oxide and nitride (1)	BL16B2
C00A16B2-420N	HAGA, Koukichi	Structure Analysis of Amorphous SiN _x Films on GaAs Substrates	BL16B2
C00A16B2-421N	HIRAI, Yasuharu	Analysis of local structure of permalloy thin films and Li-contained materials.	BL16B2
C00A16B2-422N	OKAMOTO, Tokuhiko	Fluorescence XAFS Analysis on Fe in Synthetic Protein.	BL16B2
C00A16B2-423N	TAKEMURA, Momoko	Local structure analysis of tantalum oxide films by Ta L-shell XAFS	BL16B2
C00A16B2-424N	IZUMI, Kouichi	Non-destructive characterization of Li-ion Mn battery cell by means of x-ray tomography	BL16B2
C00A16B2-425N	OHSAWA, Michio	Transmission XAFS of Ti Oxide Powder	BL16B2
C00A16B2-426N	WATANABE, Takashi	Analysis of Microstructure of Iron Rust by SR-XAFS	BL16B2
C00A16B2-427N	OKAMOTO, Tokuhiko	Local Structure Analysis on Ni, Co and Thin Oxide Film by He Ion Yield XAFS and Fluorescence	BL16B2
C00A16B2-428N	OZAKI, Shinji	He Ion Yield XAFS Analysis of Ti, Ta Films	BL16B2
C00A24XU-501N	KATSUYA, Yoshio	X-ray Structure Analyses of Amylases and Related Enzymes	BL24XU
C00A24XU-502N	KATSUYA, Yoshio	Evaluation of Biocrystallography Experimental Hutch of Hyogo Beamline(BL24XU)	BL24XU
C00A24XU-503N	HASEGAWA, Hiroshi	Study of Phase on Structural Analysis for Bioactive Molecule and Medicine for Brain Function	BL24XU
C00A24XU-504N	TANIGUCHI, Taizo	Structural and functional analysis of the dementia-causing proteins	BL24XU
C00A24XU-505N	KOIKE, Hideaki	Crystallographic study of molecular mechanism of the thermostability of DNA binding proteins	BL24XU
C00A24XU-507N	MISAKI, Shintarou	Crystallographic analysis of integrase, proteinase and lyase	BL24XU
C00A24XU-509N	YANAGI, Kazunori	Crystallographic analysis of functional organic micro crystals	BL24XU
C00A24XU-518N	KOIZUMI, Masahiro	Crystallographic analysis of complex crystal of serine protease inhibitor	BL24XU
C00A24XU-519N	SUGIO, Shigetoshi	Crystal Structure Analysis of Enzymes Associated with Signal Transduction	BL24XU
C00A24XU-523N	MORIKAWA, Kousuke	Crystallographic study of the recombinational DNA repair proteins Ruv A,B,C	BL24XU

C00A24XU-524N	INAGAKI, Eiji	Protein structure determination for medicinal development	BL24XU
C00A24XU-525N	INAGAKI, Eiji	Small Crystal Structure determination of MES	BL24XU
C00A24XU-528N	KOIZUMI, Masahiro	Crystallographic analysis of synthetic serine protease inhibitors	BL24XU
C00A24XU-531N	KANEYOSHI, Takahiro	Structural analysis of titan nitrides films using X-ray diffraction method	BL24XU
C00A24XU-532N	WATANABE, Yoshio	In situ observation of crystal surfaces / interfaces during metalorganic chemical vapor deposition	BL24XU
C00A24XU-533N	NISHIO, Kozi	In-situ Analysis of Surface Film Structure on Metal Substrates during Oxidation or Corrosion	BL24XU
C00A24XU-534N	NISHIO, Kozi	An analysis procedure for thermal barrier coating	BL24XU
C00A24XU-535N	NISHIO, Kozi	Some observations on the surface structure of ion implanted molds for rubber	BL24XU
C00A24XU-541N	MATSUI, Junji	Study of Formation of X-Ray Quasi-Plane-Wave Microbeam and Its Application	BL24XU
C00A24XU-542N	KAGOSHIMA, Yasushi	Formation of the x-ray microbeams using focusing x-ray optical elements and the development of a scanning x-ray microscope	BL24XU
C00A24XU-543N	TSUSAKA, Yoshiyuki	Development of High Resolution X-ray Imaging by the Refraction Contrast Method	BL24XU
C00A24XU-544N	NAKAYAMA, Takenori	Study on Environmental Cracking Mechanism of Structural Materials by SR	BL24XU
C00A24XU-545N	KIMURA, Shigeru	Precise x-ray diffraction measurements for local minute strain using highly parallel x-ray microbeam	BL24XU
C00A24XU-546N	IZUMI, Kouichi	Development of the technique for characterizing electronic materials by phase contrast imaging	BL24XU
C00A24XU-547N	KATOH, Takeo	Study on the surface layer of the silicon wafers	BL24XU
C00A24XU-548N	TANI, Katsuhiko	Topographic Observation of the Structure of Micro-actuator	BL24XU
C00A24XU-549N	UMEZAWA, Osamu	Characterization of subsurface microstructure and microcrack for metallic materials	BL24XU
C00A24XU-550N	NINOMIYA, Toshio	Phase-Contrast X-ray Imaging of Trace Forensic Samples	BL24XU
C00A24XU-551N	ZHANG, Yanping	X-ray refractive lenses for micro-beam technology	BL24XU
C00A24XU-554N	ANDO, Masami	Development of imaging technique using quasi-monochromatic SR with very high parallelity	BL24XU
C00A24XU-555N	TANINO, Kichiya	Synchrotron Radiation-Xray Studies of Improvement on SiC Single Crystal	BL24XU
C00A24XU-557N	NINOMIYA, Toshio	Trace Elemental Analysis of Abuse-Drugs Using Synchrotron Radiation	BL24XU
C00A44XU-700N	YAMASHITA, Eiki	Development of crystal structural analysis for macromolecular assemblies	BL44XU
C00A44XU-701N	YOSHIKAWA, Shinya	X-ray crystallographic analysis of bacterial type cytochrome c oxidase	BL44XU
C00A44XU-716N	KAKUTA, Yoshimitsu	X-ray crystallographic analysis of Ternary Complex of Human Heparan Sulfate Sulfotransferase-substrate-Inactive Cofactor	BL44XU
C00A44XU-71JN	SAKAI, Hiroaki	Studies on the reaction mechanism of NADH oxidase	BL44XU
C00A44XU-71UN	TAKENAKA, Akio	Structural Study on 2-Oxoacid Dehydrogenase Complexes	BL44XU
C00A44XU-72MN	MIKI, Kunio	Structure of Function of Supramacromolecular Molecular Chaperons	BL44XU
C00A44XU-72QN	MORIMOTO, Yukio	Crystal Structure Analyses of Salicylate hydroxylase	BL44XU
C00A44XU-72ZN	YAMAGUCHI, Hiroshi	Structure determination of intermediates of TPQ-biogenesis of copper amine oxidase	BL44XU
C00A44XU-73GN	KAI, Ysushi	Structural Analysis of Zucchini Mucicynins	BL44XU
C00A44XU-748N	NUREKI, Osamu	X-ray crystallography of multi enzyme complex of aminoacyl-tRNA synthetase	BL44XU

C00A44XU-74BN	SHIRAKIHARA, Yasuo	X-ray crystal structure analysis of $\alpha 3\beta 3\gamma$ subcomplex of F1-ATPase from a thermophilic bacterium PS3	BL44XU
C00A44XU-758N	FUKUYAMA, Keiichi	X-Ray Crystallographic Analysis of Fdx Involved in the Assembly of Iron-sulfur Clusters	BL44XU